



SILVACO

Radiation Effects Module

Total Dose and Single Event Phenomenon, Damage Inducing and Elastic Interactions

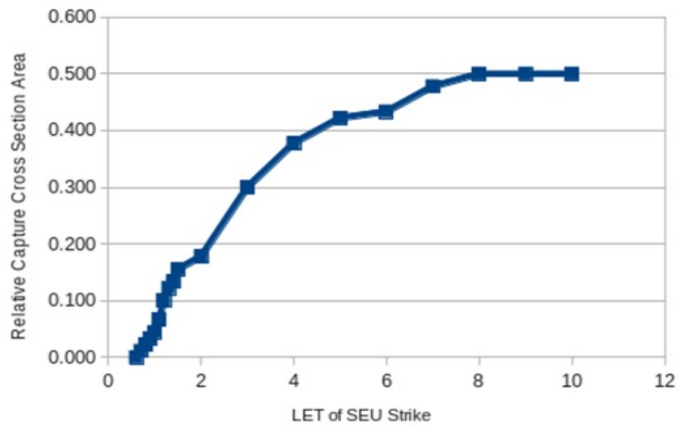
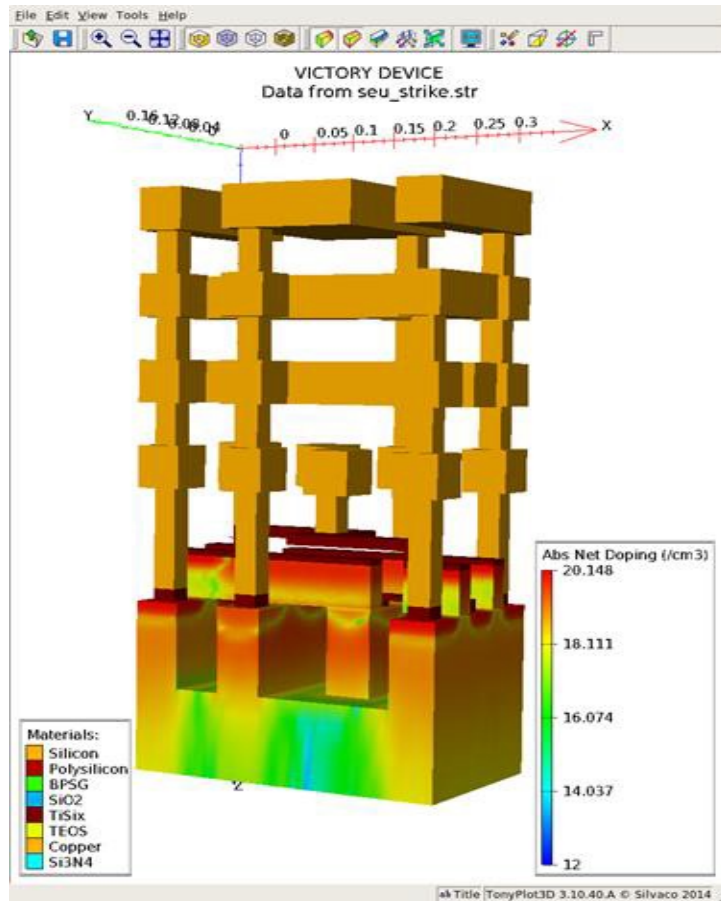
Contents

- Types of Radiation Effect
- Single Event Effects
- Total Dose Effects
- Non Damage Inducing (Temporary) Effects
- Direct Particle Damage Effects
- Indirect Destructive Damage Effects
- Conclusions

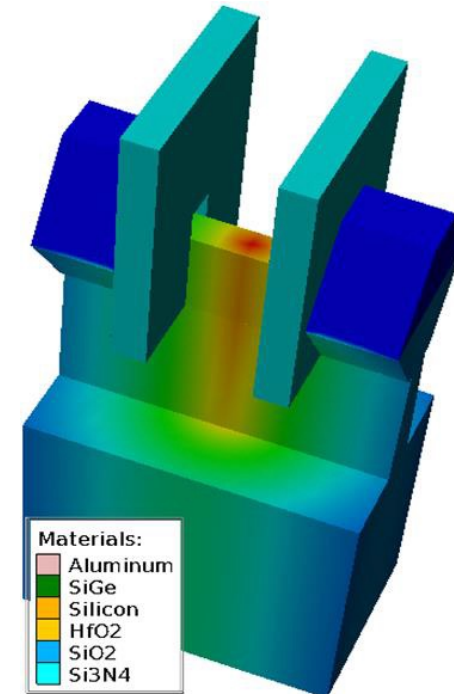
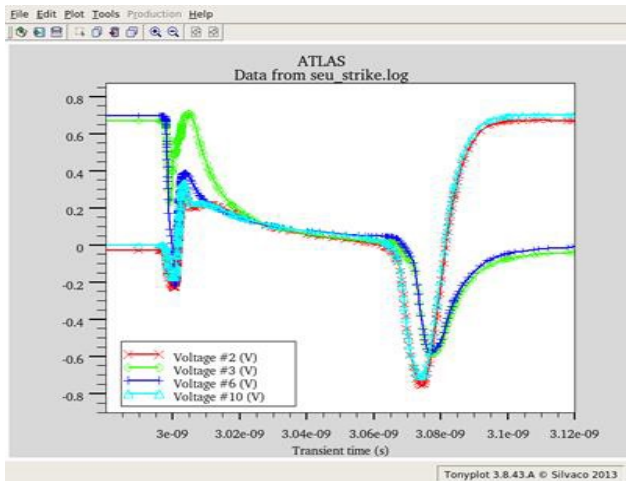
Types of Radiation Effect

- Single Event Effects
 - A single particle creates a one time local ionized charge track
- Total Dose Effects
 - The whole chip is exposed to radiation integrated over time
- Non Damage Inducing Effects
 - The effects of the radiation are temporary
- Direct Particle Damage Effects
 - The radiation particle(s) directly create the physical damage
- Indirect Destructive Damage Effects
 - Destructive secondary damage created by the circuit power supply

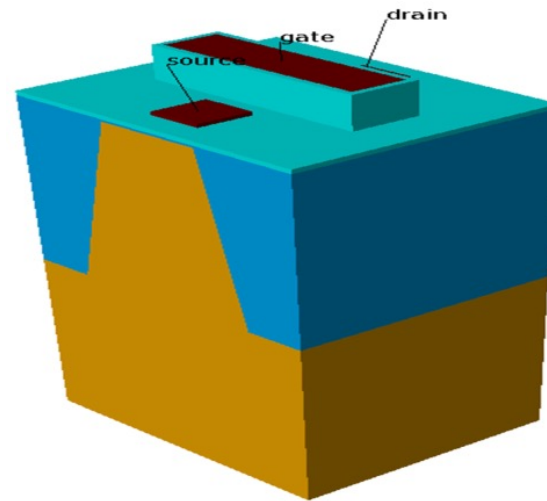
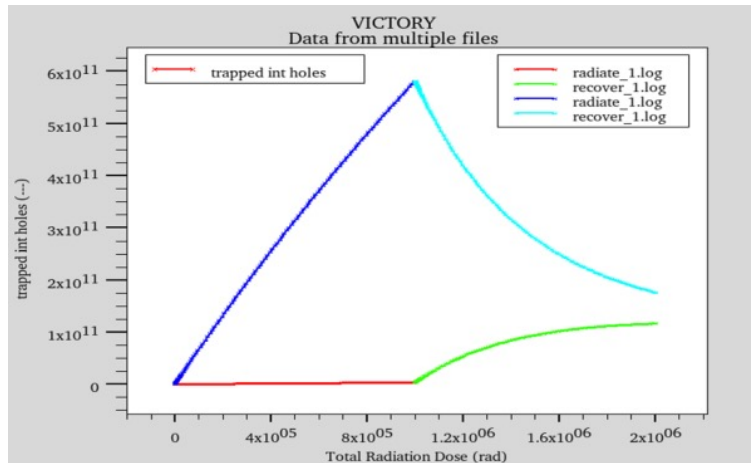
Single Event Effects



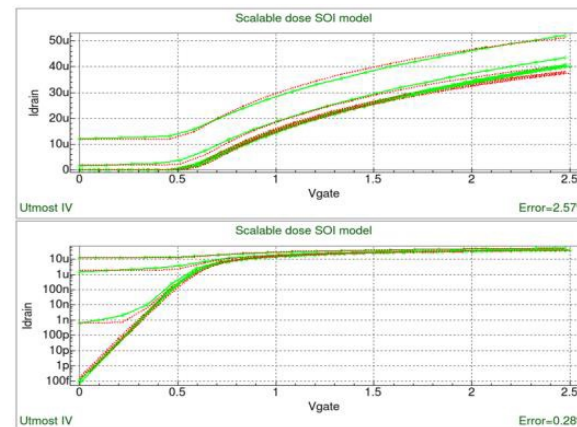
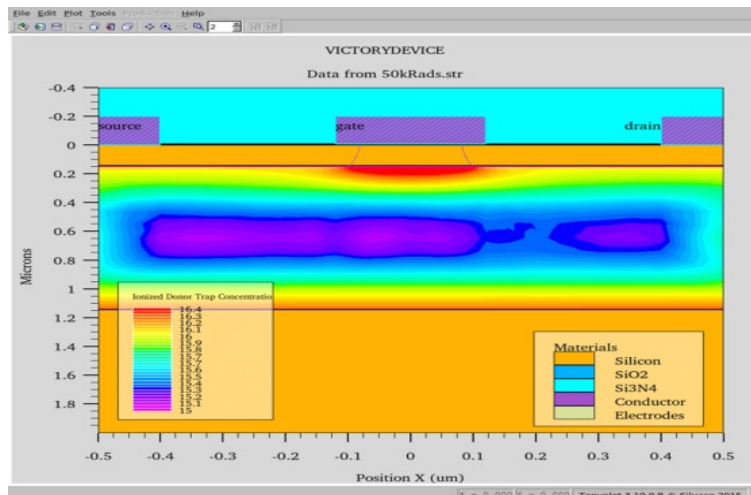
- Creates directional particle track of generated carriers
- Calculate Weibull function curves, circuit event upsets etc.



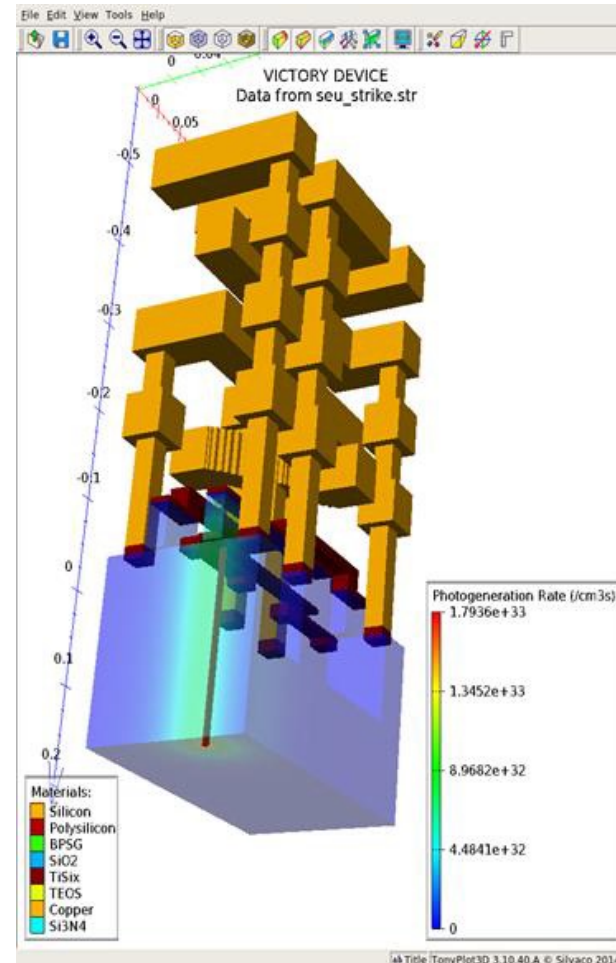
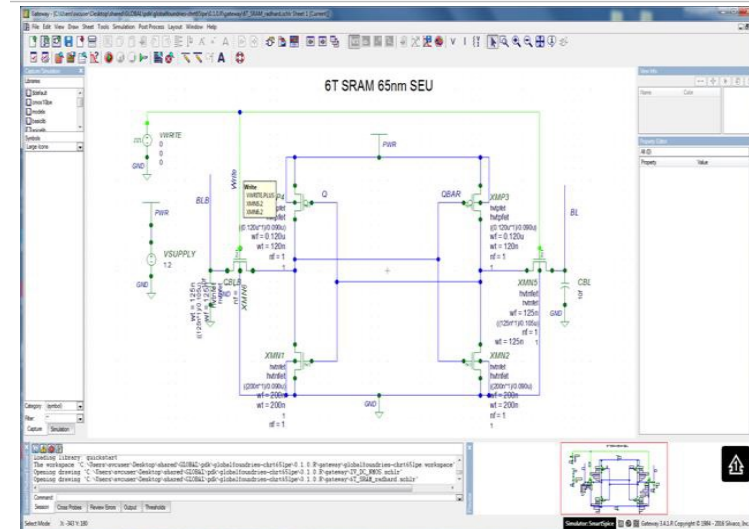
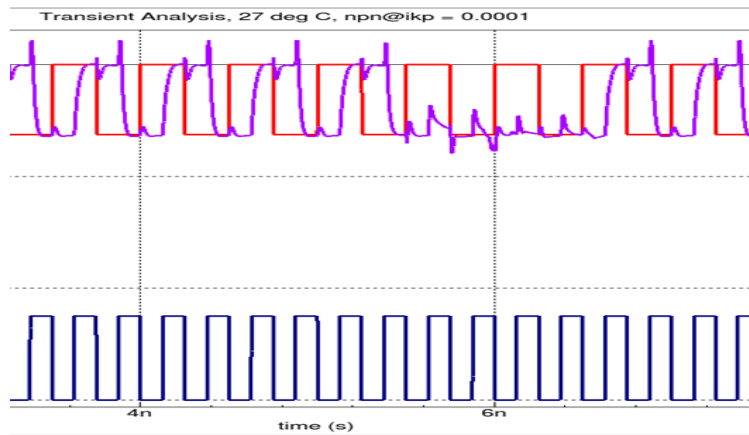
Total Dose Effects



- Unique, physically verified Silvaco model for x-ray/gamma radiation oxide hole trapping
- Vt shift and radiation induced recovery, intra and inter device leakage
- Create post radiation SPICE models using Utmost IV

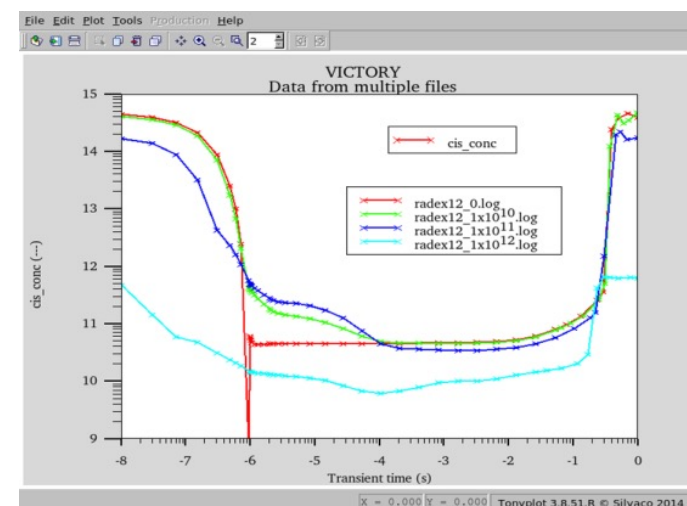
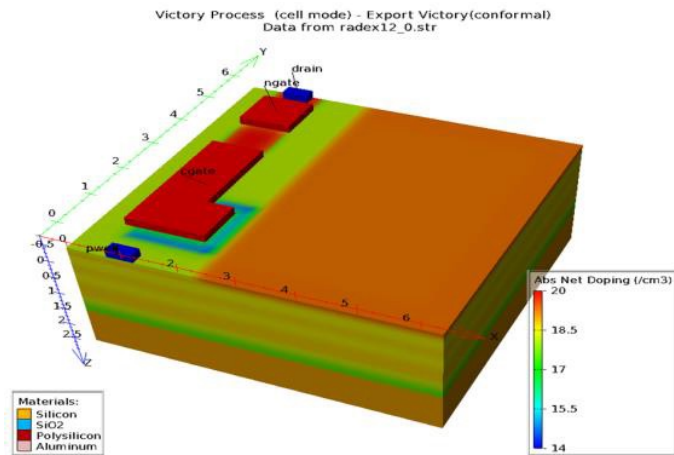
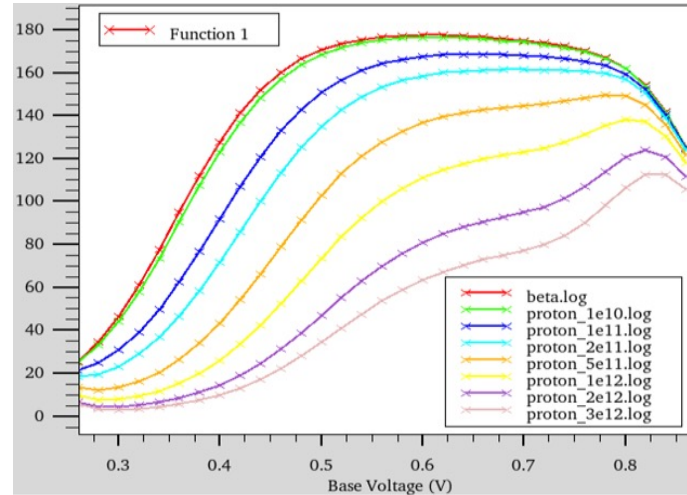
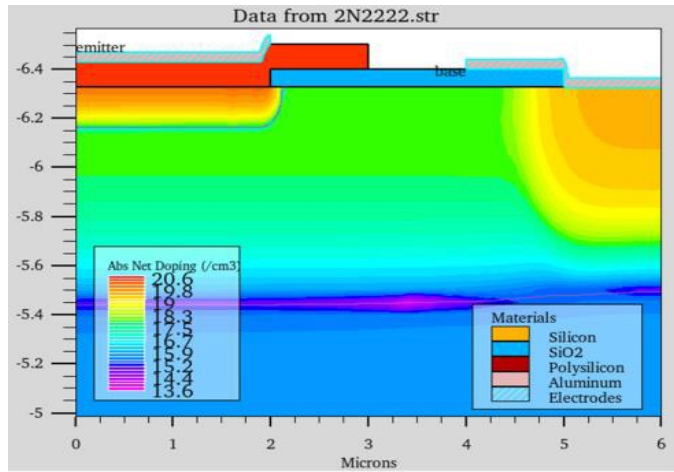


Non-Damage Inducing Effects



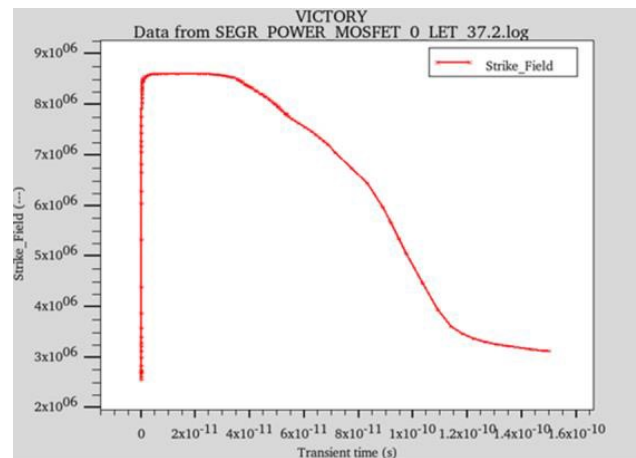
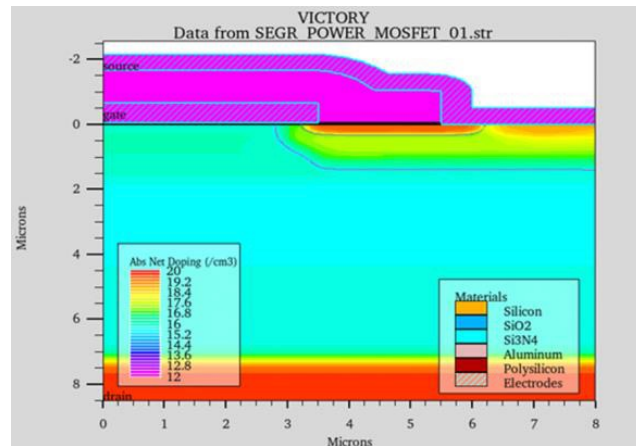
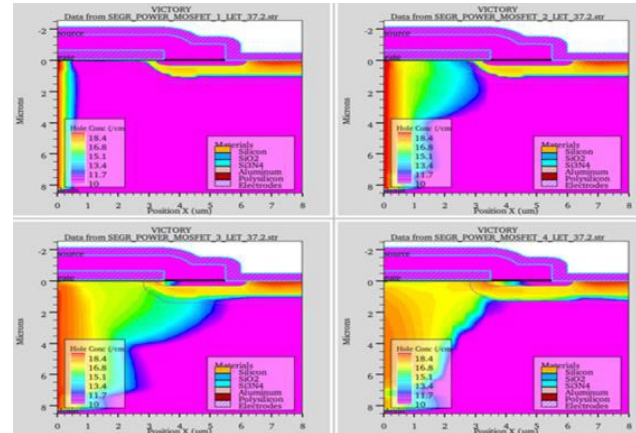
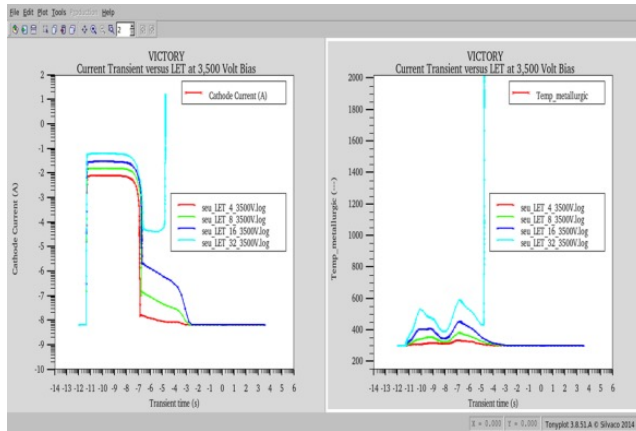
- Non damage inducing effects result in a temporary loss of circuit functionality
- These effects can be modelled purely in SmartSpice for worst case corner models, or in TCAD based “Mixed Mode” simulations, or purely TCAD simulations

Direct Particle Damage Effects



- Direct particle damage occurs as a result of high mass particle such as protons, neutrons etc.
- Crystal damage usually manifests as a reduction of free carrier lifetimes
- Lifetime sensitive devices, such as bipolar transistors or image sensors can be severely effected

Indirect Destructive Damage Effects



- Destructive damage to a device can be triggered by radiation, but the energy for the destruction, comes from the circuit power supply
- Gate oxides and high power/voltage devices are typically sensitive to such destruction

Summary

- Silvaco has solutions for most types of radiation effects
- Simulations can be SPICE only, Mixed Mode or purely TCAD
- Radiation effects can be included in SPICE model cards
- Support for ease of use features such as SEU track meshing
- DOE features for circuit sensitive capture cross section, etc.

